## Notice of References Cited Application/Control No. 09/524,358 Dishi ET AL. Examiner Andrew L. Nalven Applicant(s)/Patent Under Reexamination OISHI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,078,152	03-1978	Tuckerman, III, Louis Bryant	380/37
*	В	US-5,008,935	04-1991	Roberts, Thomas J.	380/29
*	С	US-5,241,599	08-1993	Bellovin et al.	713/171
*	D	US-5,594,793	01-1997	Bahout, Yvon	713/193
*	Ε	US-5,765,197	06-1998	Combs, James Lee	711/164
*	F	US-5,943,421	08-1999	Grabon, Robert J.	380/269
*	G	US-6,202,152	03-2001	Yuenyongsgool et al.	713/189
*	Н	US-6,378,071	04-2002	Sasaki et al.	713/165
*	-	US-6,385,727	05-2002	Cassagnol et al.	713/193
*	7	US-5,237,460	08-1993	Miller et al.	360/8
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	α			•		
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Applied Crytography, Bruce Schneier, Second Edition
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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